

Rev	Description	Appd.	Date
A	redrawn to AutoCAD	Iag	09-27-00

Notes:

1.0 Orientations

1.1 Wafer surface is normal to X axis $\pm 0.5^\circ$

1.2 Flats

1.2.1 Primary flat is normal to the +Z axis $\pm 0.5^\circ$.

1.2.2 Secondary flat is 135° clockwise from the +Z axis when viewing the -X face.

2.0 Edge

1.1 All edges rounded with $R0.70 \pm 0.08\text{mm}$.

1.2 No more than 5 edge chips 0.5mm in penetration and 1.0mm in length.

3.0 Surfaces

3.1 Side 1 <-X> face

Polished 10-5 scratch-dig with 1mm edge exclusion. No pits or scratches visible with reflected light and unaided eye.

3.2 Side 2 <+X> face

Polished 60-30 scratch-dig with 1mm edge exclusion. Light pits and scratches visible with reflected light and unaided eye allowed.

4.0 Flatness

TTV < $15\mu\text{m}$.

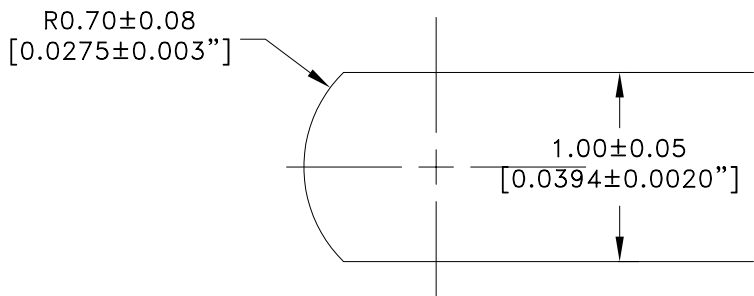
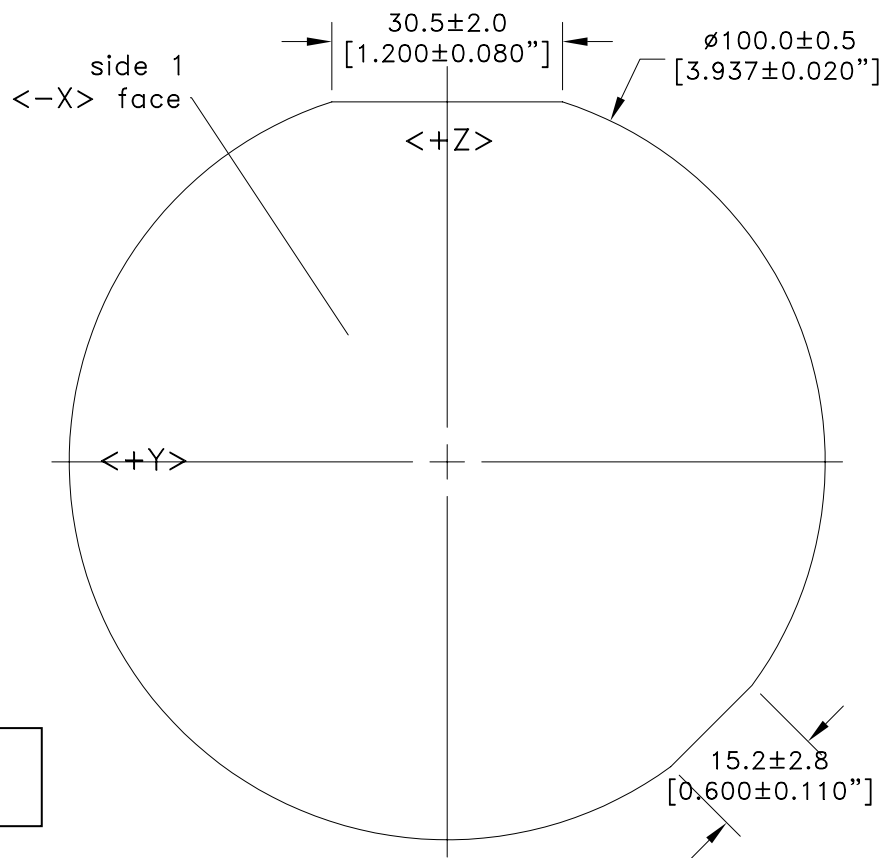
5.0 Material

Lithium Niobate G1-G2 grade.

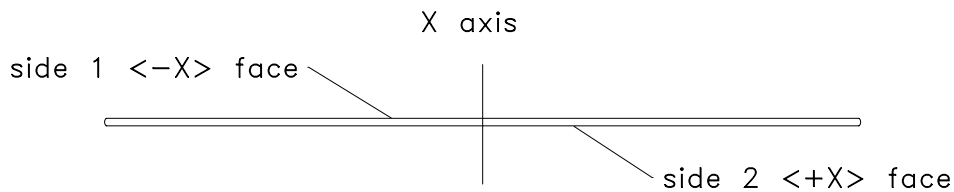
6.0 Test Data

Supply test data sheet 97-01763-01-110.


For Reference Only



Wafer Edge Detail, 25X



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Material: Lithium Niobate	DR. Igordon	09-27-00	 Crystal Technology, Inc. An EPCOS Company
Unless otherwise specified, dimensions in mm	CHK.		
Tolerances			Title: LNIO 100 ϕ x 1.0mm, -X Po/Po, +Z FLT, TTV < $15\mu\text{m}$
Inches	Millimeters	Wafer Code:	Size: A
.X \pm 0.1	X \pm 0.5	Customer Approval:	Dwg. No: 97-01763-01
.XX \pm 0.01	.X \pm 0.25		Rev: A
.XXX \pm 0.005	.XX \pm 0.1		
.XXXX \pm 0.0020	.XXX \pm 0.05		
Angles \pm 0.5°	DO NOT SCALE DRAWING		Scale: 1:1
			Sheet 1 of 1